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WB		6,879,167	4/12/05	JU ET AL.			G01R 27/04					
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WB		61-173171	04.08.1986	JAPAN (w/abstract)			G01R	27/02		<b>/</b>		
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EXAMINER /Wa			/Walter Bens	lter Benson/		DATE CONSIDERED			05/23/2006			
EXAMINE	ER: Ini ered. I	tial if citation considered, whet nclude copy of this form with n	her or not citation is in ext communication to	n conform	ance with MPEP Sect	ion 609; D	raw line thro	ough citation if no	t in conform	ance and		